

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|--|---|------------------|---------|------------------|
| L1 | 0 | Aloen\$.inv. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:22 |
| L2 | 0 | Aloen.inv. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:21 |
| L3 | 37357 | (wafer\$1 or semiconductor\$1 or chip\$1)same inspect\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:24 |
| L4 | 11445 | 3 and (defect or flaw or fault) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:24 |
| L5 | 0 | 4 and repetitive near3 (area or region) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:25 |
| L6 | 101 | 4 and repetitive near3 (area or region) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:25 |
| L7 | 10 | 6 and (nonrepetitive or non adj repetitive)near3(area or region) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:28 |
| L8 | 6 | 7 and @ad<"20011024" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:28 |
| L9 | 4 | 8 and histogram | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:34 |
| L10 | 4 | 9 and memory near3 cells | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:34 |

| | | | | | | |
|-----|---|---|---|----|----|------------------|
| L11 | 4 | 10 and(compar\$5 or match\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:35 |
| L12 | 4 | 11 and (contrast or brightness) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:37 |
| L13 | 1 | 12 and (1D or one adj dimensional\$ or 1-D) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:38 |
| L14 | 4 | 12 and dimensional\$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/21 08:39 |